

Navigating Global and Local Semiconductor Material Markets and Supply Chain

October 17, 2019

KC Hsu

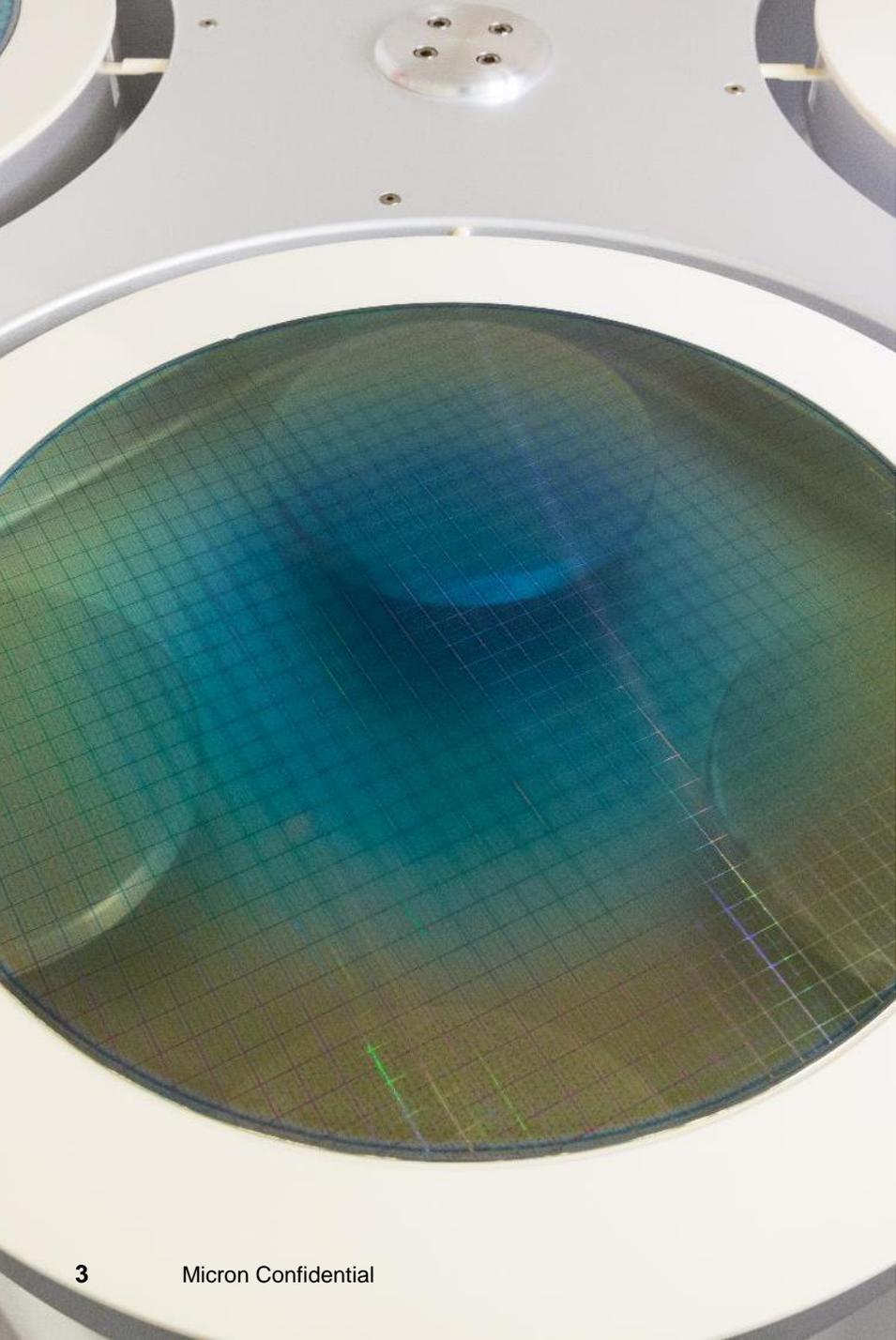
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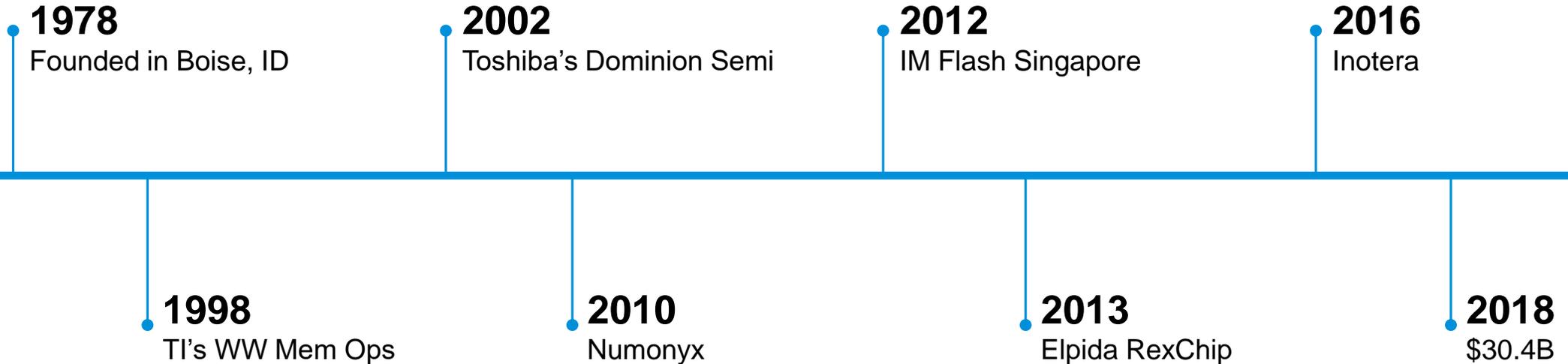
During the course of this meeting, we may make projections or other forward-looking statements regarding future events or the future financial performance of the Company and the industry. We wish to caution you that such statements are predictions and that actual events or results may differ materially. We refer you to the documents the Company files from time to time with the Securities and Exchange Commission, specifically the Company's most recent Form 10-K and Form 10-Q. These documents contain and identify important factors that could cause the actual results for the Company to differ materially from those contained in our projections or forward-looking statements. These certain factors can be found at <http://www.micron.com/certainfactors>. Although we believe that the expectations reflected in the forward-looking statements are reasonable, we cannot guarantee future results, levels of activity, performance, or achievements. We are under no duty to update any of the forward-looking statements after the date of the presentation to conform these statements to actual results.



Agenda

- Micron Introduction
- Global & Local Semiconductor Material Market
- Criticality in Material Quality
- Weakness in Material Industry
- Chemical Contamination Control & Detection System
- Micron Case Study
- Summary

40 Year Legacy



Leading Technology Innovation

Expanding Trusting Partnerships

Scaling Manufacturing & Global Footprint



Global Scale and Manufacturing Excellence

We deliver comprehensive customer collaboration, support, and quality throughout the product lifecycle and around the world.



Data Is Today's Global Currency

Sparking discovery in science and medicine.

Driving more intelligence at the edge.

Accelerating the speed of critical insights.

Inspiring new consumer experiences.

Technology Scaling Challenges

Application

DRAM

Pitch multiplication processes enable feature scaling but challenge fab space and cycle time

NAND

CVD / ETCH process progression is challenging space, capital depreciation & cycle time

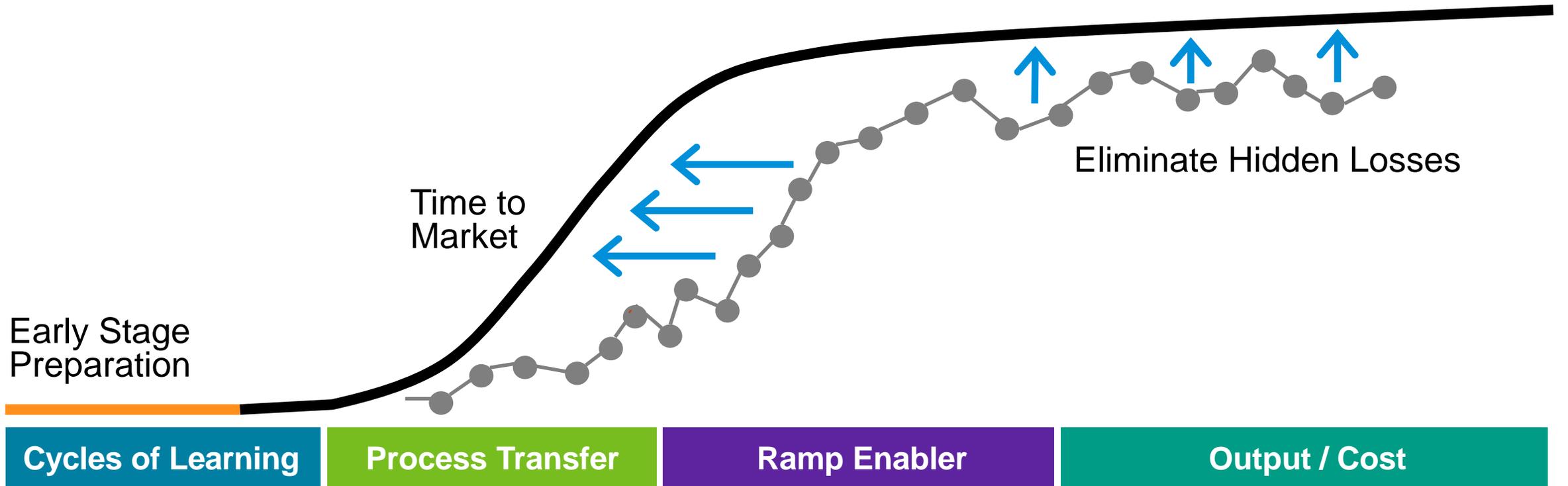
Action

Materials and process innovation to enable scaling

Disruptive equipment capability that enables linear scaling

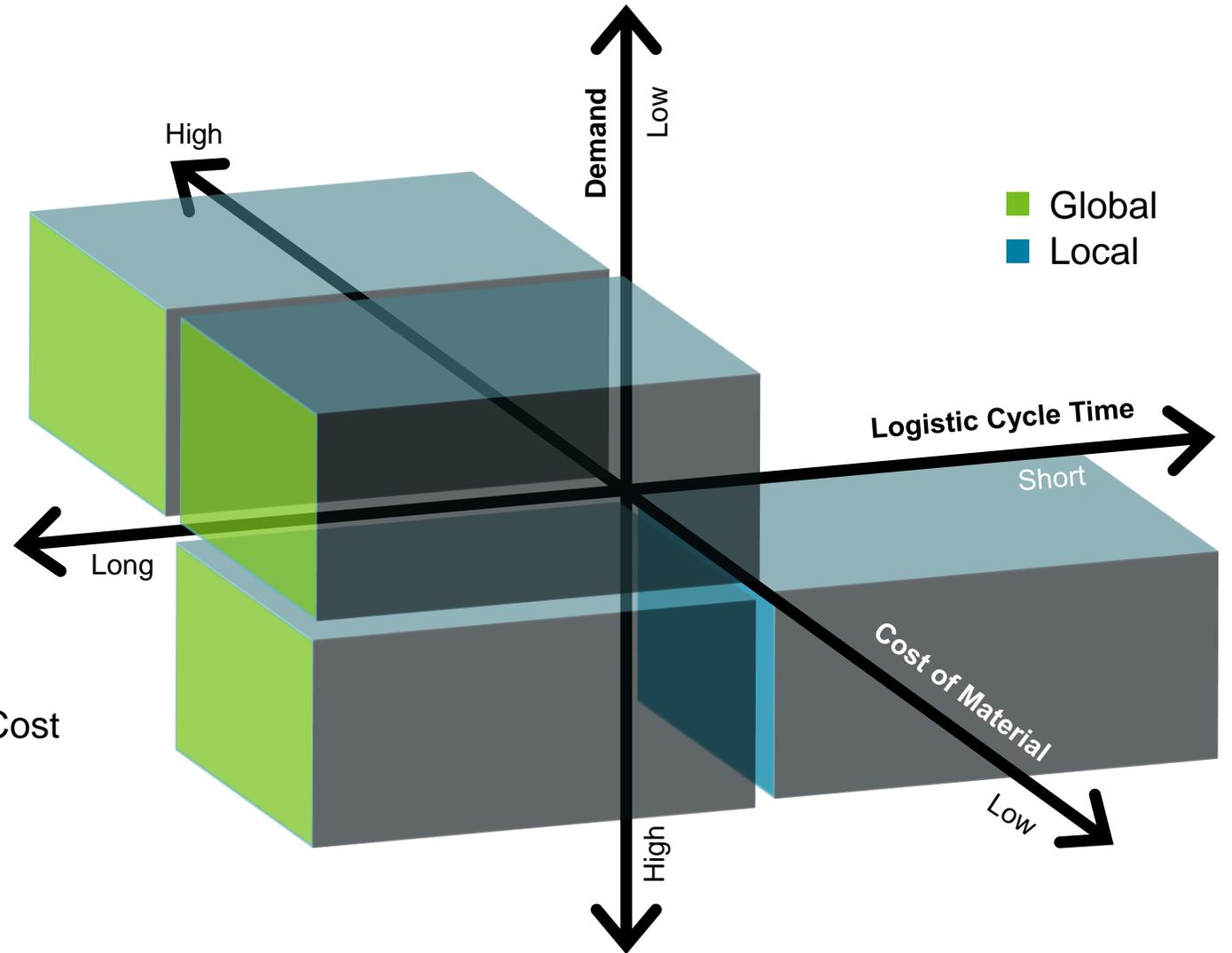
Accelerating End-to-End Solutions

Fab Manufacturing Engagement With Materials Suppliers



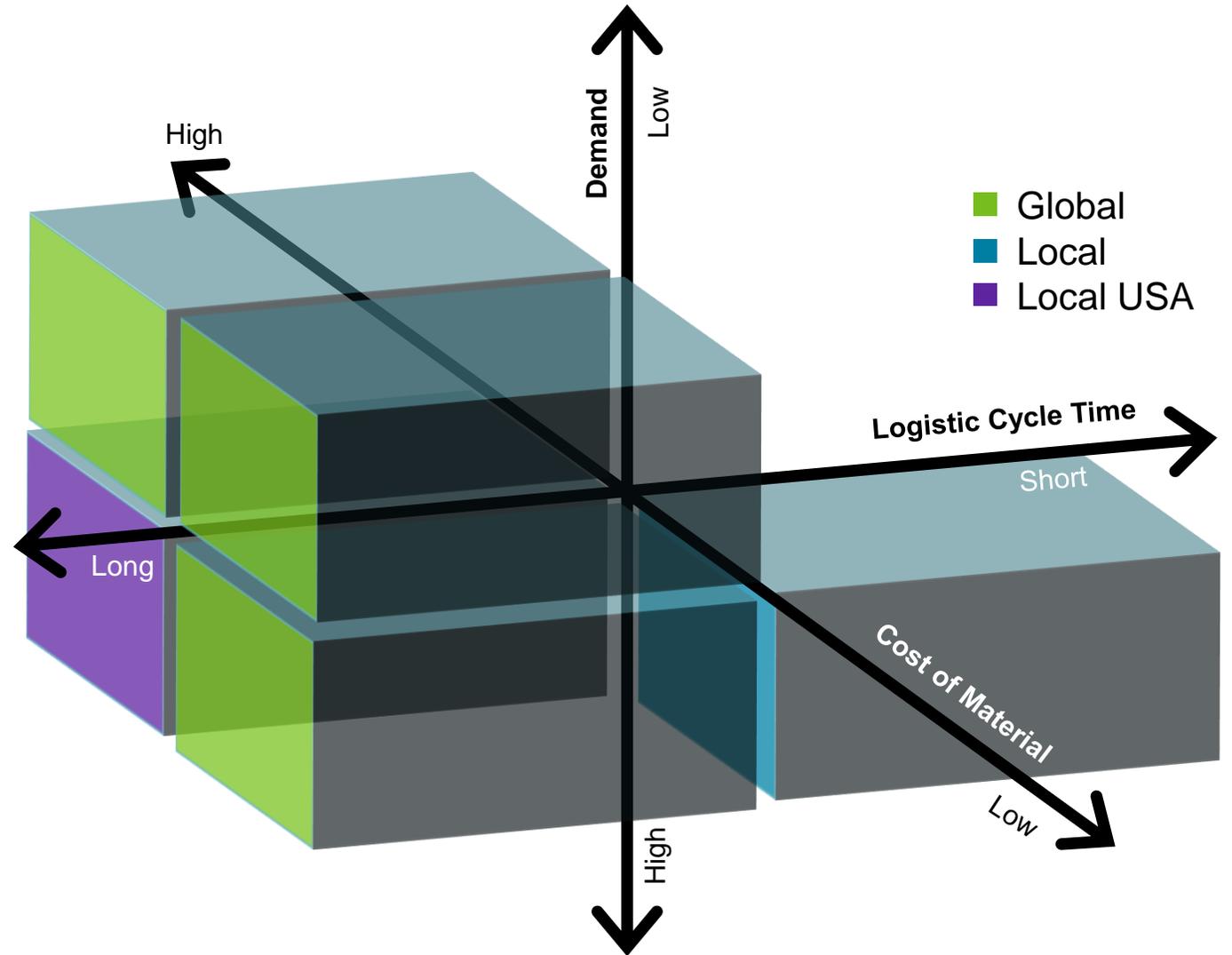
Global vs Local Semiconductor Material Market (Conventional)

- Most regional source can meet quality need
- **Local Supply** = High Demand + Low CT + Low Cost



Global vs Local Semiconductor Material Market (Quality Driven)

- North America source = quality limitation in varying sources
- Sourcing extend beyond North America to global
- **Better quality = win business**





Quality of Material is the New Game Changer to Win in Material Business in Local or Global Market

Driven by Technology Advancement in Process & OEM Capability Improvement

Weakness in Material Supply Industry

Weakness in Material Supply Industry

Task

Risk Assessment

- RA Tools lacking in some Material suppliers
- Example: FMEA tie to Control Plan
- Include packaging, valves & connectors PM Management

Detection Capability

- Organic, Metallic, Particle contamination are the challenge in industry
- Organic analysis is most immature
- Online Organic analytical system & Filtration not readily available
- 3rd Party Electronic Specialty Gas analytical capability not readily available in industry

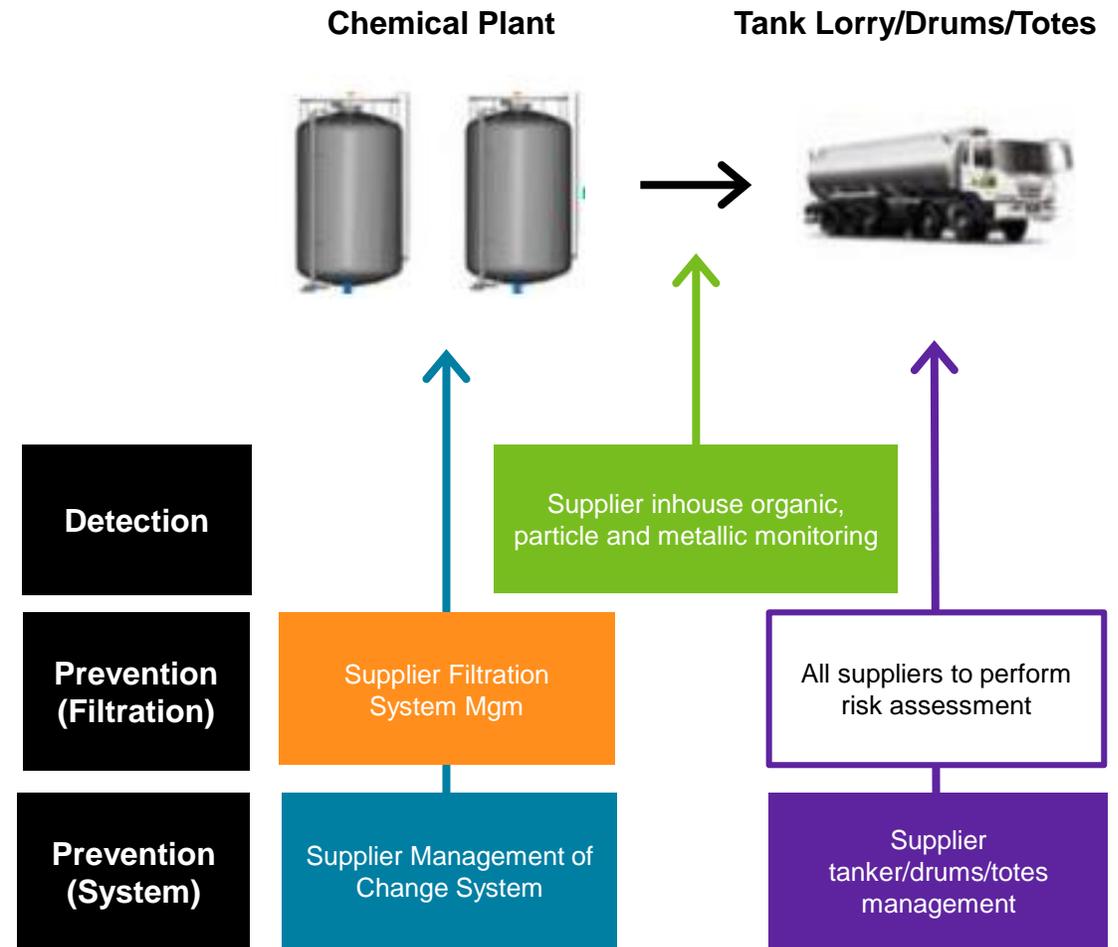
Action

- Supplier to control Manufacturing Process through Control Plans driven by FMEA.
- Supplier to take action when drift in baseline process alerted Ship to Control OOC.

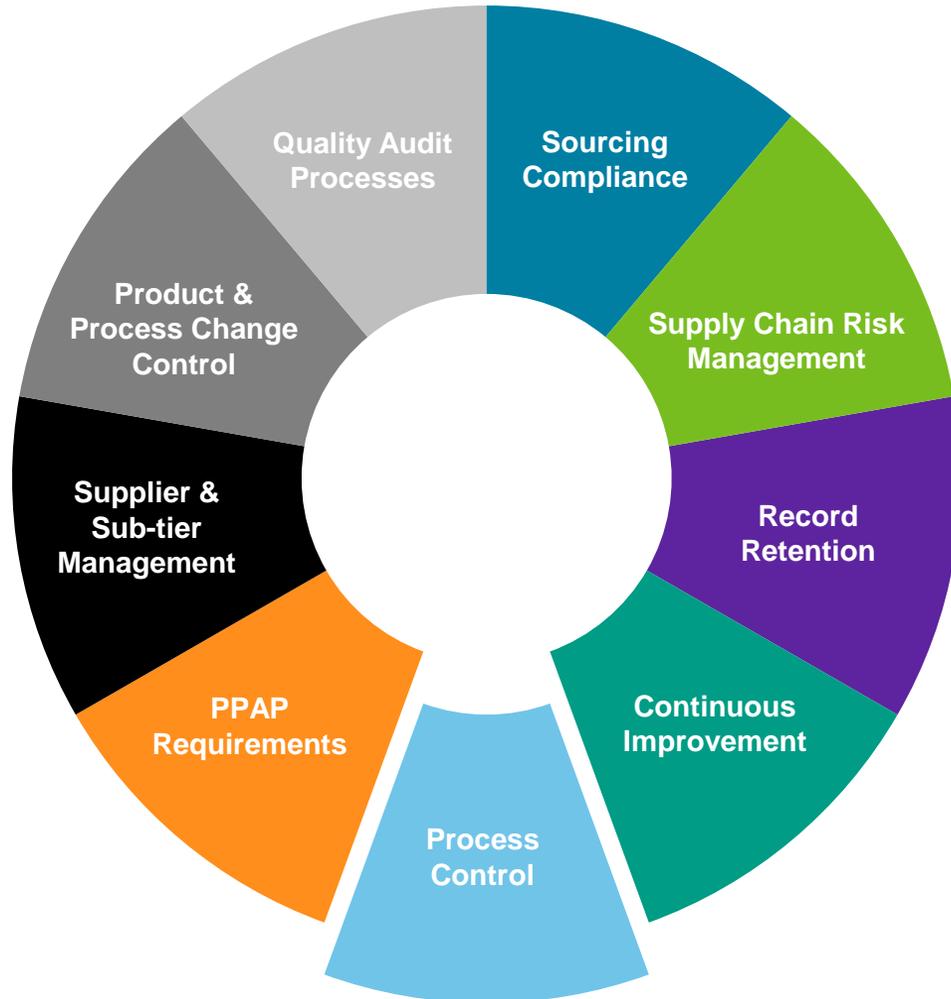
- Supplier to enhance Control Point Hardening in upstream raw material supplier.
- Supplier to upgrade Metrology Capability especially Organic, Metallic & Particles detection.

Chemical Contamination Control and Detection System

Shift Left
Early Detection
QMS



Case Study North America Region



Bulk Chemicals Incoming Quality

Issue: Organic Contamination in NH₄OH due to Inability to detect organics and no Organic specs for incoming chemicals

Source: UPW system bacteria contamination

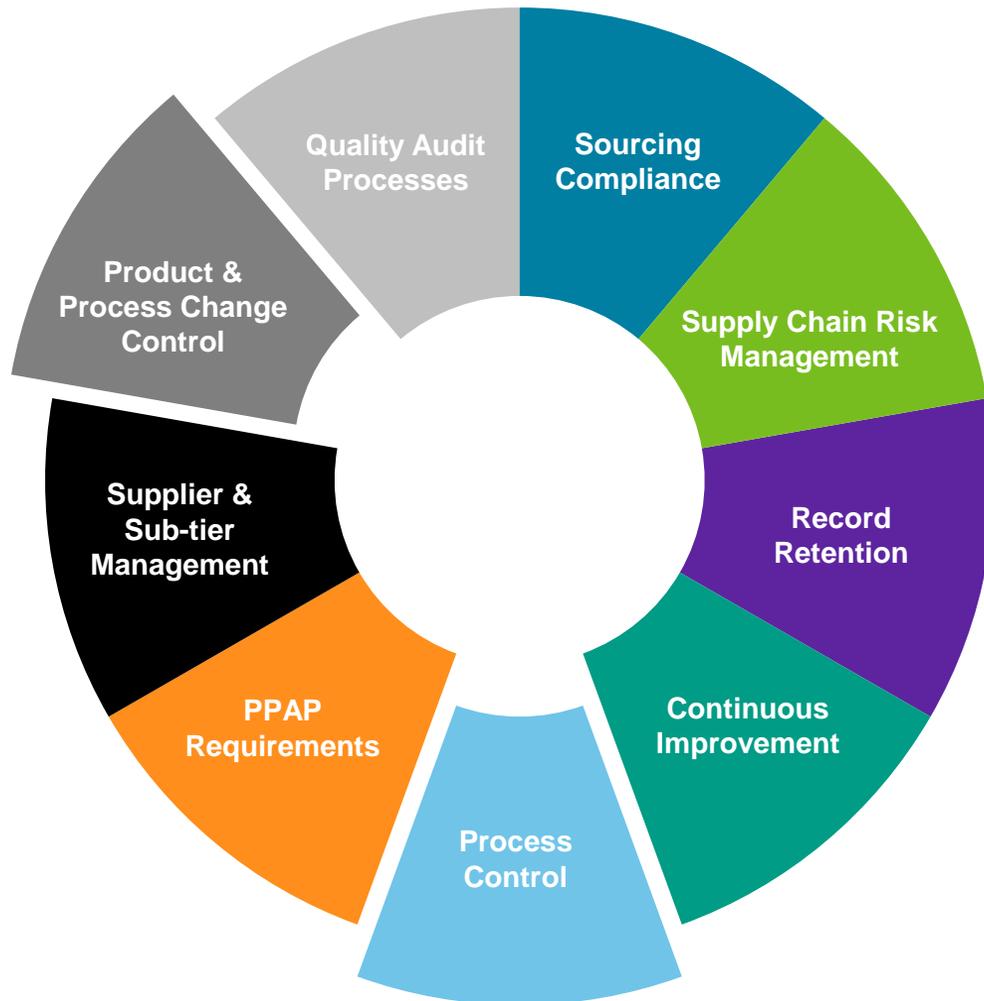
- Failure in SPC disposition when filter pressure OOC
- Failure to detect at Outgoing CoA & Inline Scan

Remedy:

- Supplier specs to include organics
- Enable organic analysis capability

Supplier Impact: Loss of business

Case Study Asia Region



Bulk Chemicals Incoming Quality and Change Control

Issue:

- Particle Contamination in IPA resulting Probe yield fallout during a conversion to different source Iso-tanker

Source:

- Improper management on contaminated Iso-tanker connection hose coupler/cap

Remedy:

- Supplier to implement proper procedure for hose/coupler/cap washing after use.

Supplier Impact: Reduced business share

Summary

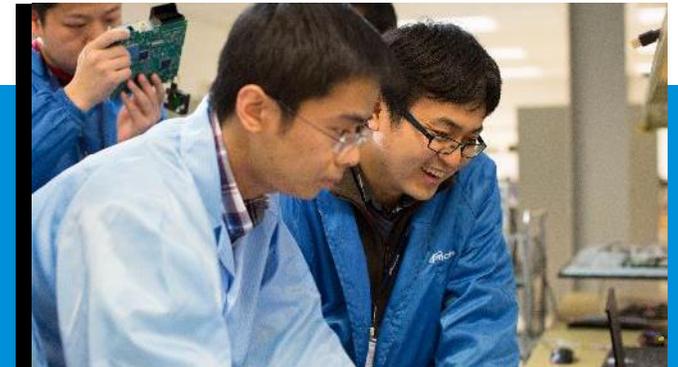
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Advance technology nodes driving a paradigm shift on current process controls.



Early detection capability is key to protect the customers enabling zero excursion.



QMS towards IATF compliance with key critical systems.



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